

COMMON ABBREVIATIONS AND ACRONYMS

AC —alternating current	FFT —fast Fourier transform	OI —operator interface
A/D —analog-to-digital	FIA —flow injection analysis	OOD —object oriented design
AEC —architect, engineer and constructor	FID —flame ionization detector	OOP —object oriented programming
AI —artificial intelligence	FIP —factory information protocol	OSI —open systems interconnection
ANDF —architecture neutral distribution format	FMS —flexible manufacturing system	P&ID —piping and instrumentation diagram
ASCII —application specific integrated circuit	FS —full scale	PB —proportional band
API —application programming interface	FTIR —Fourier transform infrared	PC —personal computer or programmable controller
ATG —automatic tank gauge	GC —gas chromatograph	PD —positive displacement
BCD —binary coded decimal	GPIB —general purpose interface bus	P/I —pneumatic-to-current
BPS —bits per second	GUI —graphical user interface	PI —proportional-integral
CAD —computer-aided design	HCFC —hydrochlorofluorocarbon	PID —proportional-integral-derivative
CAE —computer-aided engineering	HPLC —high pressure liquid chromatography	PLC —programmable logic controller
CAM —computer-aided manufacturing	HPV —high performance vane	PROM —programmable logic controller
CASE —computer-aided software engineering	HTG —hydrostatic tank gauge	PSA —pressure sensitive adhesive
C/C —center-to-center	IC —integrated circuit	PRV —pressure reducing valve
CFC —chlorofluorocarbon	I/O —input/output	PV —process variable or process value
CIE —computer integrated enterprise	ID —inside diameter	QC —quality control
CIM —computer integrated manufacturing	I/P —current-to-pneumatic	R&D —research and development
CIP —clean in place	IR —infrared	RAM —random access memory
CJC —cold junction compensation	IS —intrinsic safety	RF —radio frequency
CMOS —complementary metal oxide semi-conductor	JIT —just-in-time	RFI —radio frequency interference
CNC —computer numerical control	LAN —local area network	RH —relative humidity
CPU —central processing unit	LC —liquid chromatograph	RMS —root mean square
CRC —cyclic redundancy check	LCD —liquid crystal display	ROM —read-only memory
CRT —cathode ray tube	LCL —lower control unit	RSS —root sum squared
CSA —Canadian Standards Association	LDES —linear discrimination expert system	RTD —resistance temperature detector
CT —current transformer	LED —light emitting diode	RTU —remote terminal unit
D/A —digital-to-analog	LEL —lower explosive limit	RV —relief valve
DAS —data acquisitions system	LIMS —laboratory information management system	SCADA —supervisory control and data acquisition
DC —direct current	LP —linear programming	SCR —silicon controlled rectifier
DCE —distributed computing environment	MACT —maximum achievable control technology	SFC —supercritical fluid chromatography
DCS —distributed control system	MAP —manufacturing automation protocol	SNA —systems networking architecture
DES —discrimination expert system	MGO —magnesium oxide	SP —set point
DIN —Deutsches Institute fur Normung	MIPS —millions instructions per second	SPC —statistical process control
DMA —direct memory access	MIS —management information services	SPDT —single pole, double throw
DNC —direct numerical control	MMI —man machine interface	SQC —statistical quality control
DOS —disk operating system	MMS —manufacturing message system	SSR —solid state relay
DP —differential pressure	MTBF —meantime between failures	SSC —single station controller
DPDT —double pole, double throw	MTTD —mean time to detect	SV —set point value
DPM —digital panel meter	MTTF —mean time to fail	T/C —thermocouple
DRAM —dynamic random access memory	MODEM —modulating/demodulating module	TCD —thermal conductivity detector
EHL —effective heated length	MPCS —manufacturing planning and control software	THD —total harmonic distortion
EMI —electro magnetic interference	MRP —material requirements planning	TOP —technical office protocol
EMS —expanded memory specification	MRP II —manufacturing resource planning	TPM —total predictive maintenance
EPA —enhanced performance architecture	NC —normally closed	TQC —total quality control
EPROM —erasable, programmable read-only memory	NC —numerical control	TVSS —transient voltage surge suppressor
ERP —enterprise resource planning	NDIR —non-dispersive infrared	UCL —upper control limit
ES —expert system	NIR —near infrared	UPS —uninterruptible power supply
EVOP —evolutionary operations	NO —normally open	UV —ultraviolet
EWMA —exponentially weighted moving average	OCR —optical character recognition	VDT —video display terminal
FCS —field control station	OD —outside diameter	VFD —variable frequency drive
	OEM —original equipment manufacturer	VME —virtual memory executive system
		WAN —wide area network
		WIP —work-in-process